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# ***IC TEST MARKETS AND TRENDS***

**2008 EDITION**

**A Strategic Report  
On The Global IC Test Industry**

## **Report Highlights**

- **Industry Overview**
  - ◆ **World Economic Outlook**
  - ◆ **Semiconductor Industry Outlook**
- **Technical Trends**
  - ◆ **Test Basics**
  - ◆ **Test Issues Reducing**
  - ◆ **Test Cost**
  - ◆ **Semiconductor Test ConsortiumMarket**
- **Analysis and Forecast, 2007–2012**
  - ◆ **IC Units**
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  - ◆ **Contract Test Market**
- **Company Profiles**

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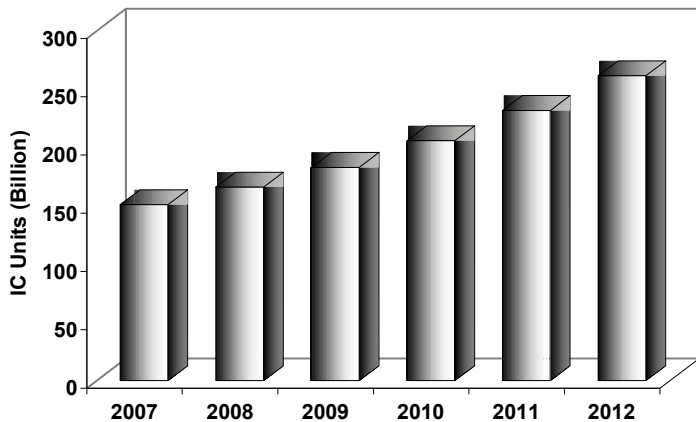
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# IC Test Markets and Trends, 2008 Edition

## Synopsis

Since the end of 2001, annual IC unit shipments have grown an astounding 120 percent. Will this torrid growth continue? If so, what are the implications for the IC test industry? *New Venture Research (NVR)*, in the **2008 Edition of IC Test Market and Trends**, analyzes the semiconductor industry and uses this analysis to forecast the future of the global IC test market.

The report begins with *NVR's* views on the state of the semiconductor industry. This discussion includes a look at global economic factors that may impact the industry. *NVR's* base semiconductor forecast (see Figure 1) and a mid-year update to that forecast are also provided.



**Figure 1 IC Unit Forecast**

Next, the report presents a brief overview of the technical trends in IC testing. Final test basics and

issues are presented. Methods for reducing the cost of final test—including parallel or multi-site testing—are emphasized. The activities of the Semiconductor Test Consortium are reviewed.

Following the technical overview, the report presents final test cost forecasts for each semiconductor product type. This forecast includes units,

revenue, and ASP for each product, so that the reader may compare test costs with product revenue. Test cost detail includes estimates for test times (seconds), testing costs (dollars per second), unit test cost (dollars per IC), total product test cost, and test cost as a percentage of product revenue.

Forecasts are also presented for the contract test services market. To help you further assess the companies participating in contract testing, the report profiles the activities of the world's largest contractors and the services they offer.

The report also profiles a group of key equipment and software companies involved in semiconductor test.

**IC Test Markets and Trends, 2008 Edition** will provide you with an effective and economical tool for assessing the future of IC testing. The report is delivered by email as a single-user PDF file. The report sells for \$1995, with extra single-user licenses at \$250 each. Corporate licensing is available—contact us for pricing!

## About the Authors

**Sandra Winkler** is the senior analyst for IC packaging at New Venture Research (NVR). She began her analyst career as an independent consultant to the telecommunications industry nearly 20 years ago. Since 1995, Ms. Winkler has authored all of NVR's widely cited reports on IC packaging. She has spoken at numerous industry conferences and has written articles for a variety of trade publications. Ms. Winkler has an MBA from Santa Clara University.

**Steve Berry** was President and Principal Analyst of Electronic Trend Publications (ETP). Mr. Berry has been responsible for the direction of all aspects of ETP's broad-ranging research portfolio since 1993. In the eighteen years prior to joining ETP, he held a variety of engineering, manufacturing management, and business development positions with General Electric and Xerox. Mr. Berry holds a BS in Engineering from North Carolina State University and an MBA from Stanford University.

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AIC	IS Test Lab
Amkor Technology	KYEC
ASAT Limited	Lingse Millennium
ASE Test	Micro
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Chant WorldChipTest	Powertech
ChipMOS	Semiteq
CEI	Signetics
Cirtek	Sigurd
CORWIL	Siliconware
Das Test Haus	SPEL Semi
DSL Labs	STATS ChipPAC
EEMS	ThaiLin
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